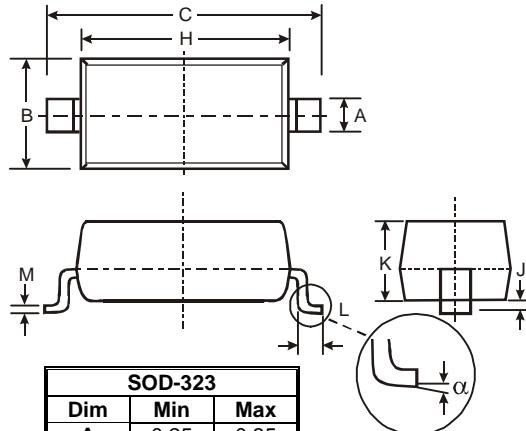


Features

- These diodes are also available in other case styles including the DO35 case with the type designation 1N4148, the MiniMELF case with the type designation LL4148, and the SOT23 case with the type designation IMBD4148-V
- Silicon epitaxial planar diode
- Fast switching diodes
- Lead (Pb)-free component
- Component in accordance to RoHS 2002/95/EC and WEEE 2002/96/EC

Mechanical Data

- **Case:** SOD323 plastic case
- **Weight:** approx. 4.3 mg
- **Packaging Codes/Options:**
GS18/10 k per 13" reel (8 mm tape), 10 k/box
GS08/3 k per 7" reel (8 mm tape), 15 k/box



SOD-323		
Dim	Min	Max
A	0.25	0.35
B	1.20	1.40
C	2.30	2.70
H	1.60	1.80
J	0.00	0.10
K	1.0	1.1
L	0.20	0.40
M	0.10	0.15
α	0°	8°

All Dimensions in mm

Maximum Ratings and Electrical Characteristics

• $T_A = 25^\circ\text{C}$ unless otherwise specified

Parameter	Test condition	Symbol	Value	Unit
Reverse voltage		V_R	75	V
Repetitive peak reverse voltage		V_{RRM}	100	V
Average rectified current half wave rectification with resistive load	$f \geq 50 \text{ Hz}$	$I_{F(AV)}$	150 ¹⁾	mA
Surge forward current	$t < 1 \text{ s}$ and $T_j = 25^\circ\text{C}$	I_{FSM}	350	mA
Power dissipation		P_{tot}	200 ¹⁾	mW
Parameter	Test condition	Symbol	Min	Typ.
Forward voltage	$I_F = 10 \text{ mA}$	V_F		1000
	$I_F = 100 \text{ mA}$	V_F		1200
Leakage current	$V_R = 20 \text{ V}$	I_R		25
	$V_R = 75 \text{ V}$	I_R		5
	$V_R = 100 \text{ V}$	I_R		100
	$V_R = 20 \text{ V}, T_j = 150^\circ\text{C}$	I_R		50
Diode capacitance	$V_F = V_R = 0 \text{ V}$	C_D		4
Voltage rise when switching ON (tested with 50 mA pulses)	tested with 50 mA pulses, $t_p = 0.1 \mu\text{s}$, rise time < 30 ns, $f_p = (5 \text{ to } 100) \text{ kHz}$	V_{fr}		2.5
Reverse recovery time	$I_F = 10 \text{ mA}, I_R = 1 \text{ mA}, V_R = 6 \text{ V}, R_L = 100 \Omega$	t_{rr}		4
Rectification efficiency	$f = 100 \text{ MHz}, V_{RF} = 2 \text{ V}$	η_v	0.45	

Note:

¹⁾ Valid provided that electrodes are kept at ambient temperature.

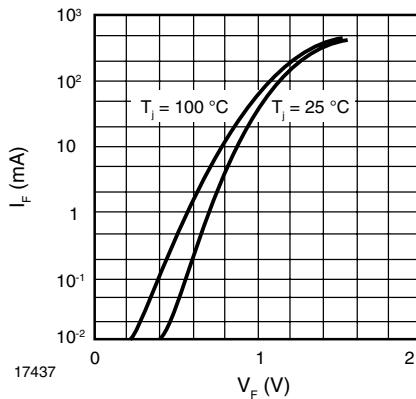


Figure 1. Forward characteristics

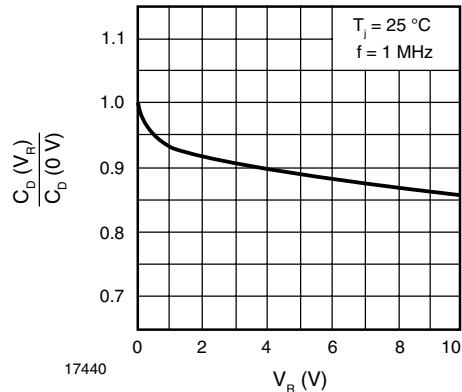


Figure 4. Relative Capacitance vs. Reverse Voltage

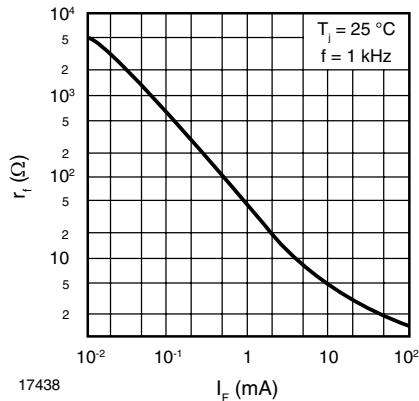


Figure 2. Dynamic Forward Resistance vs. Forward Current

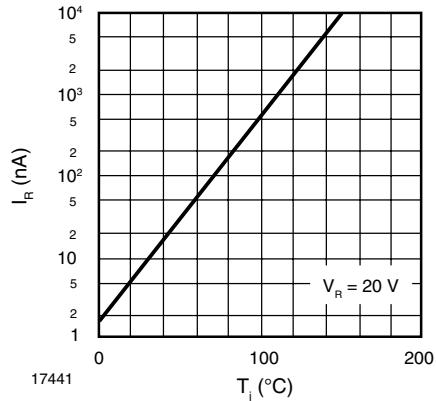


Figure 5. Leakage Current vs. Junction Temperature

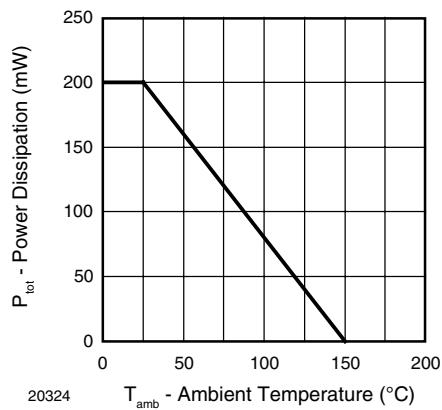


Figure 3. Admissible Power Dissipation vs. Ambient Temperature

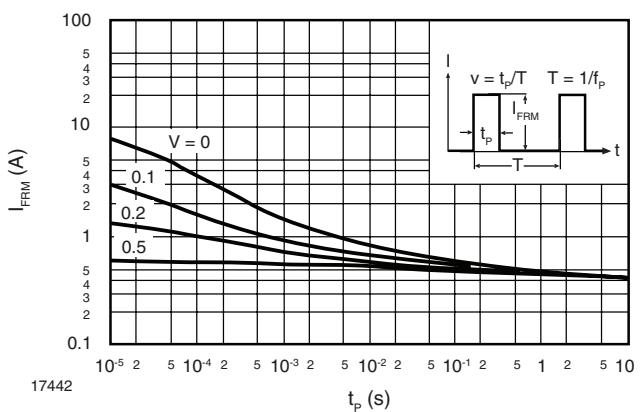


Figure 6. Admissible Repetitive Peak Forward Current vs. Pulse Duration